

means for storing the measured first current;
means for supplying a read potential to gate terminals of the row or column to be read;
means for measuring a resulting second current flowing through the row or column to be read; and
means for comparing the second current with the stored first current.

Claim 7 (Currently Amended): A method for operating a memory having memory transistors arranged in a group, a drive circuit coupled to a memory transistor of the group so that information can be written to and read from the memory transistor, and a selection transistor coupled with the group of memory transistors so that the group of memory transistors can be jointly selected, the method comprising the steps of:

~~opening~~applying a high potential to the gate terminal of the selection transistor while gate terminals of the memory transistors of the group of memory transistors are at low potential;
measuring a first current flowing through each row or column to be read;
storing the measured first current;
supplying a read potential to gate terminals of the row or column to be read;
measuring a resulting second current flowing through the row or column to be read; and
comparing the second current with the stored first current.